

1. Record Nr.	UNINA9910693478403321
Titolo	Secret law and the threat to democratic and accountable government [[electronic resource] ] : hearing before the Subcommittee on the Constitution of the Committee on the Judiciary, United States Senate, One Hundred Tenth Congress, second session, April 30, 2008
Pubbl/distr/stampa	Washington : , : U.S. G.P.O., , 2008
Descrizione fisica	iii, 175 pages : digital, PDF file
Collana	S. hrg. ; ; 110-604
Soggetti	Official secrets - United States Rule of law - United States Constitutional law - United States Transparency (Ethics) in government - United States
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Title from title screen (viewed on Feb. 13, 2009). "Serial no. J-110-89."
Nota di bibliografia	Includes bibliographical references.

2. Record Nr.	UNINA9911019362203321
Titolo	X-ray spectrometry : recent technological advances // edited by Kouichi Tsuji, Jasna Injuk, Rene Van Grieken
Pubbl/distr/stampa	Chichester, West Sussex, England ; ; Hoboken, NJ, USA, : Wiley, c2004
ISBN	9786610238880 9781280238888 1280238887 9780470020425 0470020423 9780470020432 0470020431
Descrizione fisica	1 online resource (617 p.)
Altri autori (Persone)	Tsujikouichi InjukJasna GriekenR. van (Rene)
Disciplina	543/.62
Soggetti	X-ray spectroscopy
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	X-Ray Spectrometry: Recent Technological Advances; Contents; Contributors; Preface; 1 Introduction; 1.1 Considering the Role of X-ray Spectrometry in Chemical Analysis and Outlining the Volume; 2 X-Ray Sources; 2.1 Micro X-ray Sources; 2.2 New Synchrotron Radiation Sources; 2.3 Laser-driven X-ray Sources; 3 X-Ray Optics; 3.1 Multilayers for Soft and Hard X-rays; 3.2 Single Capillaries X-ray Optics; 3.3 Polycapillary X-ray Optics; 3.4 Parabolic Compound Refractive X-ray Lenses; 4 X-Ray Detectors; 4.1 Semiconductor Detectors for (Imaging) X-ray Spectroscopy 4.2 Gas Proportional Scintillation Counters for X-ray Spectrometry 4.3 Superconducting Tunnel Junctions; 4.4 Cryogenic Microcalorimeters; 4.5 Position Sensitive Semiconductor Strip Detectors; 5 Special Configurations; 5.1 Grazing-incidence X-ray Spectrometry; 5.2 Grazing-exit X-ray Spectrometry; 5.3 Portable Equipment for X-ray Fluorescence Analysis; 5.4 Synchrotron Radiation for Microscopic X-ray

Fluorescence Analysis; 5.5 High-energy X-ray Fluorescence; 5.6 Low-energy Electron Probe Microanalysis and Scanning Electron Microscopy  
5.7 Energy Dispersive X-ray Microanalysis in Scanning and Conventional Transmission Electron Microscopy  
5.8 X-Ray Absorption Techniques; 6 New Computerisation Methods; 6.1 Monte Carlo Simulation for X-ray Fluorescence Spectroscopy; 6.2 Spectrum Evaluation; 7 New Applications; 7.1 X-Ray Fluorescence Analysis in Medical Sciences; 7.2 Total Reflection X-ray Fluorescence for Semiconductors and Thin Films; 7.3 X-Ray Spectrometry in Archaeometry; 7.4 X-Ray Spectrometry in Forensic Research; 7.5 Speciation and Surface Analysis of Single Particles Using Electron-excited X-ray Emission Spectrometry  
Index

---

Sommario/riassunto

X-Ray Spectrometry: Recent Technological Advances covers the latest developments and areas of research in the methodological and instrumental aspects of x-ray spectrometry. Includes the most advanced and high-tech aspects of the chemical analysis techniques based on x-rays  
Introduces new types of X-ray optics and X-ray detectors, covering history, principles, characteristics and future trends  
Written by internationally recognized scientists, all of whom are eminent specialists in each of the sub-fields  
Sections include: X-Ray Sources, X-Ray Optics, X-Ray Detectors, Spec

---